PCN Number: 20190329001.1 Mar 29, 2019 **PCN Date:** Title: Qualification of Aizu as an additional Fab site for select CMOS7 devices **Customer Contact: PCN Manager** Dept: **Quality Services Estimated Sample** Date provided at **Proposed 1st Ship Date:** Jun 29, 2019 **Availability:** sample request. **Change Type: Assembly Process** Assembly Materials Assembly Site **Electrical Specification** Mechanical Specification Design Test Process Test Site Packing/Shipping/Labeling Wafer Bump Site Wafer Bump Material Wafer Bump Process Wafer Fab Process Wafer Fab Site Wafer Fab Materials Part number change

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its AIZU fabrication facility as an additional Wafer Fab source for the selected devices listed in "Product Affected" section.

Current Sites			Additional Sites		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
MAINEFAB	CMOS7	200mm	AIZU	CMOS7	200mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of supply.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
MAINEFAB	CUA	USA	South Portland

Additional Fab Site:

AIZU	CU2	JPN	Aizuwakamatsu-shi
New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City

Sample product shipping label (not actual product label)





(1P) SN74LS07NSR (P) 0336 31T)LOT: 3959047MLA 4W) TKY(1T) 7523483S12 (20L) CSO: SHE (21L) CCO:USA

Product Affected:

DAC128S085CIMT/NOPB DAC128S085CIMTX/NOPB DAC128S085CISQ/NOPB DAC128S085CISQX/NOPB

Qualification Report

Approve Date 18-Mar-2019

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: DAC128S085CIMT/NOPB	QBS Process Reference: LM3242TME/NOPB	QBS Process Reference: LP5521TM/NOPB
AC	Autoclave 121C	96 Hours	-	-	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	3/90/0	-	-
ELFR	Early Life Failure Rate, 125C	125C(Tj=125C; 48 Hrs; ATE @ 25C)	-	3/2400/0	-
ELFR	Early Life Failure Rate, 125C	125C(Tj=125C; 10k eprom precon before EFR; 48 Hrs; ATE @ 25C)	-	-	3/2400/0
HAST	Biased HAST, 110C/85%RH	264 Hours	-	-	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	2500 V	1/3/0	3/9/0	3/9/0
CDM	ESD - CDM	1000 V	1/3/0	3/9/0	-
LU	Latch-up	Per JESD78	1/6/0	3/18/0	3/18/0
HTOL	Life Test, 125C	1000 Hours	1/77/0	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	1/77/0
MISC	EPROM Memory Retention, 250C	82 Hours	-	-	3/231/0
TC	Temperature Cycle, -40/125C	1000 Cycles	-	-	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	-
YLD	FTY and Bin Summary	-	Pass	-	-
YLD	MPY and Bin Summary	-	Pass	-	-

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN www admin_team@list.ti.com

⁻ QBS: Qual By Similarity - Qual Device DAC128S085CIMT/NOPB is qualified at LEVEL1-260CG

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

⁻ The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

⁻ The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

⁻ The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles